

FCC TEST REPORT

APPLICANT Y Soft Corporation, a.s.

PRODUCT NAME **USB Card Reader**

MODEL NAME MU03015

TRADE NAME USB Card Reader v3 LF+

BRAND NAME Y Soft SafeQ

XUY0YX0MU03015 FCC ID

47 CFR Part 15 Subpart B STANDARD(S)

TEST DATE 2017-05-24 to 2017-06-01

: 2017-06-03 ISSUE DATE

SHENZHEN MORLAB COMMUNICATIONS TECHNOLOGY Co., Ltd.

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	Change History				
Issue	Issue Date Reason for change				
1.0	2017-06-03	First edition			



Test Report Declaration

Applicant	Y Soft Corporation, a.s.
Applicant Address	U Kněžské louky 2151/18, Praha 3, 130 00, Czech Republic
Manufacturer	Y Soft Corporation, a.s.
Manufacturer Address	Czech Technology Park, Technická 2948/13, 616 00 Brno, Czech Republic
Product Name	USB Card Reader
Model Name	MU03015
Brand Name	Y Soft SafeQ
HW Version	N/A
SW Version	N/A
Test Standards	47 CFR Part 15 Subpart B
Test Result	PASS

Tested by

Approved by

Andy Yeh (Technical Director)



1. Technical Information

Note: Provided by applicant

1.1. Applicant Information

Y Soft Corporation, a.s. Company:

Address: U Kněžské louky 2151/18, Praha 3, 130 00, Czech Republic

1.2. Equipment under Test (EUT) Description

EUT Type:	JSB Card Reader	
Serial No:	N/A, marked #1 by test site)	
Hardware Version: N/A		
Software Version:	N/A	

NOTE:

- The EUT is a USB Card Reader which supports RFID TX 125KHz band.
- 2. The EUT is equipped with a Micro USB port which can be connected to ancillary equipments.
- 3. For a more detailed description, please refer to specification or user's manual supplied by the applicant and/or manufacturer.



2. Test Results

2.1. Applied Reference Documents

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Test Date	Result
1	15.107	Conducted Emission	2017.05.26	PASS
2	15.109	Radiated Emission	2017.05.27	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2014.



3. **Test Conditions Setting**

3.1. **Test Mode**

The EUT configuration of the emission tests is EUT + PC.

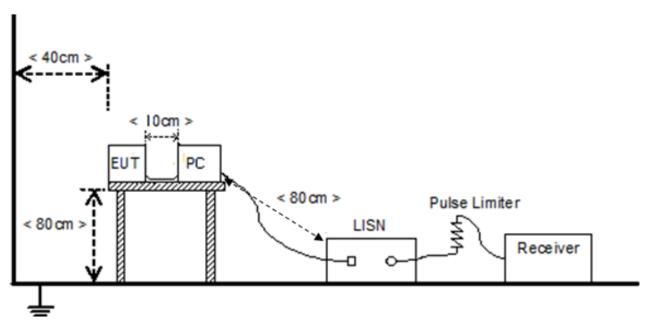
In this test mode, the EUT was connected to a PC via the Micro-B USB port and charged by the PC, meanwhile, the EUT was working normally as an intentional device.



Test Setup and Equipments List

3.2.1. Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides $50\Omega/50\mu H$ of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

The power strip or extension cord has been investigated to make sure that the LISN integrity in maintained with respect to the impedance characteristics as prescribed in ANSI C63.4-2014 at Clause 4.3.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9010	595WX11007	2017.05.17	2018.05.16
LISN	Schwarzbeck	NSLK 8127	812744	2017.05.17	2018.05.16
Pulse Limiter (20dB)	VTSD	9561D	9537	2016.07.05	2017.07.04
PC	Apple	A1370	C02FQ2PYDD QW	N/A	N/A



C. Test Software Utilized

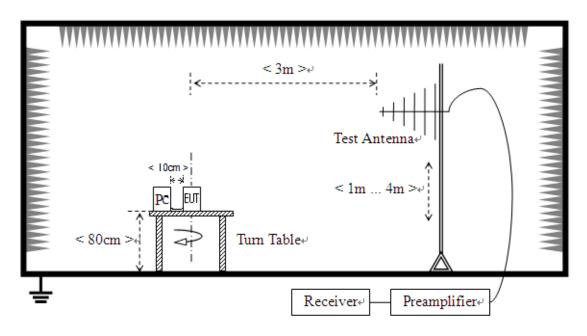
Model	Version Number	Producer
PMM Emission Suite	Version 2.05	Narda



3.2.2. Radiated Emission

A. Test Setup:

1. For radiated emissions from 30MHz to1GHz



The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table, and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
MXE EMI Receiver	Agilent	N9038A	MY54130016	2017.05.17	2018.05.16
Semi-Anechoic Chamber	Changning	9m*6m*6m	N/A	2017.01.11	2018.01.10
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2016.12.09	2017.12.08



Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
PC	DC Apple A1270		C02FQ2PYDD	NI/A	NI/A
PC	Apple	A1370	QW	N/A	N/A

C. Test Software Utilized

Model	Version Number	Producer
MORLAB EMCR V1.2	Version 1.0	MORLAB



47 CFR Part 15B Requirements

Conducted Emission 4.1.

4.1.1. Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a $50\mu H/50\Omega$ line impedance stabilization network (LISN).

Frequency range	Conducted	Limit (dΒμV)
(MHz)	Quasi-peak	Average
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50MHz.

4.1.2. Test Description

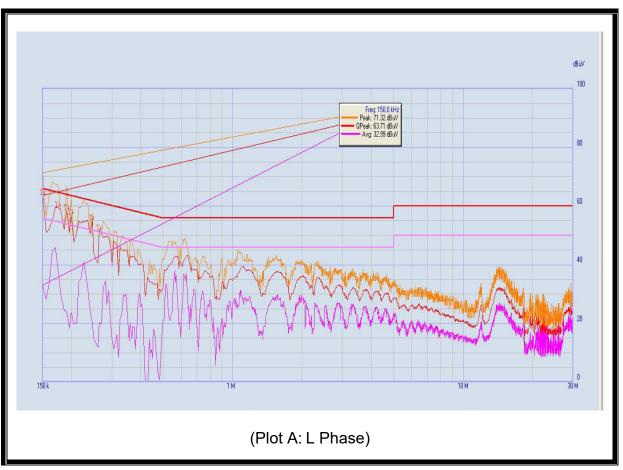
See section 3.2.1 of this report.

4.1.3. Test Result

The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

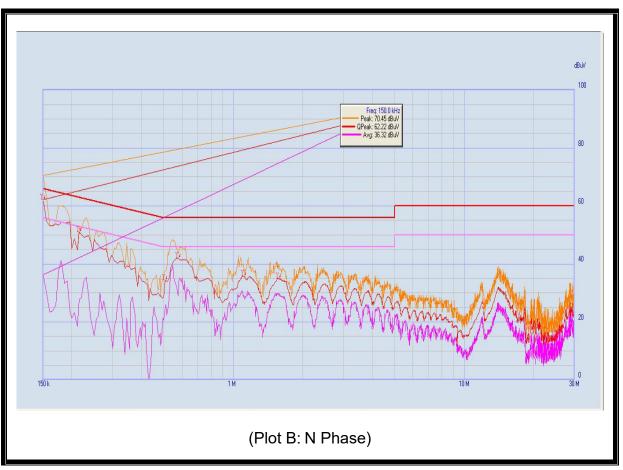
A. Test Plot and Suspicious Points:





No.	Fre.	' '		Limit (dBμV)		Power-line	Verdict
	(MHz)	Quai-peak	Average	Quai-peak	Average		
1	0.15	63.71	32.99	66.00	56.00		PASS
2	0.175	59.61	38.33	65.29	55.29		PASS
3	0.19	58.63	23.89	64.86	54.86	Lino	PASS
4	0.20	56.96	23.83	64.57	54.57	Line	PASS
5	0.245	55.04	20.40	63.29	53.29		PASS
6	0.265	51.65	20.30	62.71	52.71		PASS





No.	Fre.	. ' '		Limit (dBµV)		Power-line	Verdict
	(MHz)	Quai-peak	Average	Quai-peak	Average		
1	0.15	62.22	36.32	66.00	56.00		PASS
2	0.215	51.07	27.62	64.14	54.14		PASS
3	0.505	34.43	24.36	56.00	46.00	Neutral	PASS
4	0.575	42.01	28.97	56.00	46.00	Neutrai	PASS
5	1.11	35.77	29.14	56.00	46.00		PASS
6	1.57	34.91	29.91	56.00	46.00		PASS

Result: Pass



4.2. Radiated Emission

4.2.1. Requirement

According to FCC section 15.109 (a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency	Field Strength Limitation at 3m Measurement Dist					
range (MHz)	(μV/m)	(dBµV/m)				
30.0 - 88.0	100	20log 100				
88.0 - 216.0	150	20log 150				
216.0 - 960.0	200	20log 200				
Above 960.0	500	20log 500				

As shown in FCC section 15.35 (b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in dBμV/m is calculated by 20log Emission Level (μV/m).

4.2.2. Test Description

See section 3.2.2 of this report.

4.2.3. Frequency range of measurement

According to 15.33(b) (1), the frequency range of radiated measurement for the EUT is listed in the following table:



Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measure- ment range (MHz)
Below 1.705 1.705–108 1.08–500 500–1000 Above 1000	30. 1000. 2000. 5000. 5th harmonic of the highest frequency or 40 GHz, whichever is lower.

The highest frequency of the internal sources of the EUT is less than 108MHz, the measurement shall only be made up to 1G.

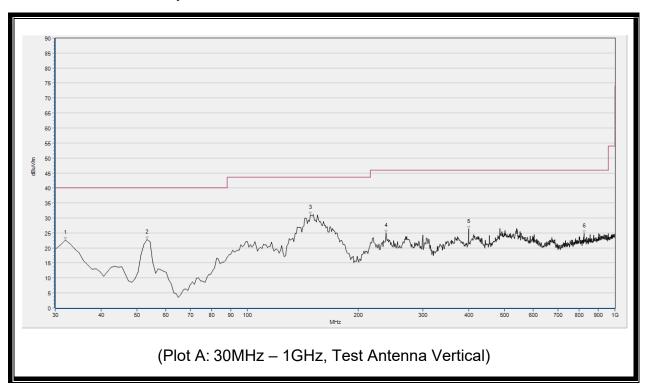
4.2.4. Test Result

The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

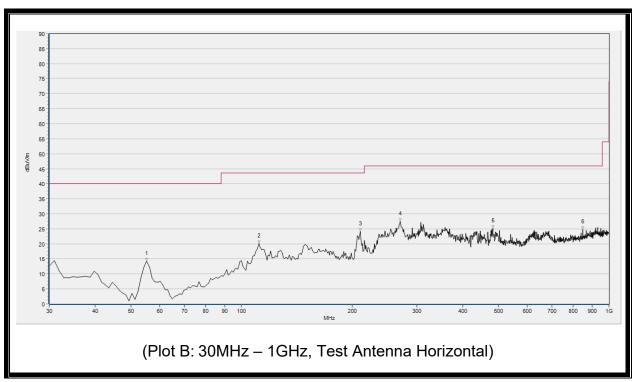


A. Test Plots and Suspicious Points:



No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m		
1	31.940	N.A.	22.62	N.A.	N.A.	40.00	N.A.	V	PASS
2	53.280	N.A.	22.83	N.A.	N.A.	40.00	N.A.	V	PASS
3	148.340	N.A.	30.93	N.A.	N.A.	43.50	N.A.	V	PASS
4	238.550	N.A.	24.89	N.A.	N.A.	46.00	N.A.	V	PASS
5	399.570	N.A.	26.31	N.A.	N.A.	46.00	N.A.	V	PASS
6	823.460	N.A.	24.73	N.A.	N.A.	46.00	N.A.	V	PASS





No.	Fre.	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	ANT	Verdict
	MHz	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m	dBµV/m		
1	55.220	N.A.	14.27	N.A.	N.A.	40.00	N.A.	Н	PASS
2	111.480	N.A.	20.07	N.A.	N.A.	43.50	N.A.	Н	PASS
3	210.420	N.A.	24.12	N.A.	N.A.	43.50	N.A.	Н	PASS
4	270.560	N.A.	27.47	N.A.	N.A.	46.00	N.A.	Н	PASS
5	482.990	N.A.	25.11	N.A.	N.A.	46.00	N.A.	Н	PASS
6	849.650	N.A.	24.87	N.A.	N.A.	46.00	N.A.	Н	PASS

Result: Pass



Annex A Test Setup photos

1. Mains Terminal Disturbance Voltage Measurement



2. Conducted emission main's port side view





3. Radiated emission (30MHz-1GHz)





Test Uncertainty Annex B

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

` ',:	•
Uncertainty of Conducted Emission:	±1.8dB
Uncertainty of Radiated Emission:	±3.1dB



Testing Laboratory Information Annex C

Identification of the Responsible Testing Laboratory

Company Name:	Shenzhen Morlab Communications Technology Co., Ltd.
Department:	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang
	Road, Block 67, BaoAn District, ShenZhen, GuangDong
	Province, P. R. China
Responsible Test Lab Manager:	Mr. Su Feng
Telephone:	+86 755 36698555
Facsimile:	+86 755 36698525

Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd.
	Morlab Laboratory
Address:	FL.3, Building A, FeiYang Science Park, No.8 LongChang
	Road, Block 67, BaoAn District, ShenZhen, GuangDong
	Province, P. R. China

3. Accreditation Certificate

Accredited Testing Laboratory: The FCC registration number is 695796.

(Shenzhen Morlab Communications Technology Co., Ltd.)

Test Environment Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 - 106

***** END OF REPORT *****